

Report No.: HKEM210800085403 Page: 1 of 11

# **TEST REPORT**

Application No.:	HKEM2108000854AT
Applicant:	BINATONE ELECTRONICS INTERNATIONAL LIMITED
Address of Applicant:	25/F, Guangdong Investment Tower, 148 Connaught Road Central, Sheung Wan, Hong Kong
Equipment Under Test (EUT	):
EUT Name:	Video Baby Monitor
Model No.:	Nursery View Pro (BU), NV531BU (Share NP540PU)
Additional Model:	Please refer to section 2 of this report which indicates which item was actually tested and which were electrically identical.
Trademark:	Hubble
FCC ID:	VLJ-NV531BU
IC:	4522A-NV531BU
HVIN:	NV531BU
Standard(s) :	47 CFR Part 1.1307; 47 CFR Part 2.1093
	KDB447498D01 General RF Exposure Guidance v06
	RSS102 Issue 5 March 2015
Date of Receipt:	2021-08-10
Date of Test:	2021-08-27 to 2021-09-10
Date of Issue:	2021-09-15
Test Result:	Pass*

\* In the configuration tested, the EUT complied with the standards specified above.

#### Law Man Kit **EMC Manager**

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Unless otherwise stated the results shown in this test report refer only to the sample(s) tested and such sample(s) are retained for 30 days only.

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01		2021-09-15		Original	

Authorized for issue by:		
	Zen Xn.	
	Leo Xu /Project Engineer	Date: 2021-09-15
	Laus	
	Law Man Kit	
	/Reviewer	Date: 2021-09-15



### 2 Test Summary

Radio Spectrum Teo	chnical Requirement			
Item	Standard	Method	Requirement	Result
RF Exposure	47 CFR Part 1.1307, 47 CFR Part 2.1093, KDB 447498 D01	KDB447498D01	KDB447498D01	PASS
RF Exposure	RSS102 Issue 5	RSS-102 Section 2.5.1	RSS102 Issue 5	PASS

#### **Declaration of EUT Family Grouping:**

Item no.: Nursery View Pro (BU), NV531BU (Share NP540PU)

According to the confirmation from the applicant, the above models are identical in all electrical aspects in relating to the circuit design, PCB layout, electrical components used, internal wiring and functions. The differences are only the model name.

Therefore, only the model Nursery View Pro (BU) was tested in this report.

#### Abbreviation:

- Rx: In this whole report Rx (or rx) means Receiver.
- RF: In this whole report RF means Radiated Frequency.
- CH: In this whole report CH means channel.
- Volt: In this whole report Volt means Voltage.
- Temp: In this whole report Temp means Temperature.
- Humid: In this whole report Humid means humidity.
- Press: In this whole report Press means Pressure.
- N/A: In this whole report not application.



Report No.: HKEM210800085403 Page: 4 of 11

### 3 Contents

		Page
1 0	COVER PAGE	1
2 1	TEST SUMMARY	3
3 (	CONTENTS	4
4 (	GENERAL INFORMATION	5
4.1	DETAILS OF E.U.T.	5
4.2	DESCRIPTION OF SUPPORT UNITS	6
4.3		
4.4		7
4.5		7
4.6	Abnormalities from Standard Conditions	7
5 F	RADIO SPECTRUM TECHNICAL REQUIREMENT	8
5.1	RF Exposure	8
5	5.1.1 Test Requirement:	8
5	5.1.1 IC Radiofrequncy radiation	9
5	5.1.2 EUT RF Exposure Evaluation	
6 F	PHOTOGRAPHS	11



## 4 General Information

### 4.1 Details of E.U.T.

Power supply:	Model: YWK-AD050100-U
	Input: AC 100-240V, 50/60Hz, Max 0.3A
	Output: DC 5V, 1000mA
Test voltage:	AC 120V
Cable:	Power Cable: 185cm unshielded 2 wires DC cable
Antenna Gain:	0 dBi
Antenna Type:	Integral antenna
Modulation Type:	FHSS: GFSK
Number of Channels:	FHSS: 22
Operation Frequency:	FHSS: 2402MHz to 2477MHz
Series number:	A1
Hardware Version:	V1.0
Software Version:	RC08
	Remark: Power level setting was not adjustable and fixed default through SW Version.



#### Frequency List

FHSS:

Channel Number	TX Freq (MHz)	Channel Number	TX Freq (MHz)
1	2402	12	2445
2	2404	13	2450
3	2406	14	2455
4	2408	15	2460
5	2410	16	2465
6	2415	17	2467
7	2420	18	2469
8	2425	19	2471
9	2430	20	2473
10	2435	21	2475
11	2440	22	2477

Remark: 1. Operation channel is total 22.

2. Testing Channels are highlighted in **bold**.

#### 4.2 Description of Support Units

The EUT has been tested with corresponding accessories as below: Supplied by client

Description	Manufacturer	Model No.	SN/Certificate NO
UART Test board	N/A	N/A	N/A

Supplied by SGS:

Description	Manufacturer	Model No.	SN/Certificate NO
NoteBook (EMC4)	Dell	P75F	N/A



#### 4.3 Test Location

All tests were performed at: SGS Hong Kong Limited Unit 2 and 3, G/F, Block A, Po Lung Centre, 11 Wang Chiu Road, Kowloon Bay, Kowloon, Hong Kong Tel: +852 2305 2570 Fax: +852 2756 4480

No tests were sub-contracted.

#### 4.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

#### • IAS Accreditation (Lab Code: TL-817)

SGS Hong Kong Limited has met the requirements of AC89, IAS Accreditation Criteria for Testing Laboratories, and has demonstrated compliance with ISO/IEC Standard 17025:2017, General requirements for the competence of testing and calibration laboratories. This organization is accredited to provide the services specified in the scope of accreditation maintained on the IAS website (www.iasonline.org).

The report must not be used by the client to claim product certification, approval, or endorsement by IAS, NIST, or any agency of the Federal Government.

#### • FCC Recognized Accredited Test Firm(CAB Registration No.: 514599)

SGS Hong Kong Limited has been accredited and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Designation Number: HK0015, Test Firm Registration Number: 514599.

#### • Industry Canada (Site Registration No.: 26103; CAB Identifier No.: HK0015)

SGS Hong Kong Limited has been recognized by Department of Innovation, Science and Economic Development (ISED) Canada as a wireless testing laboratory. The acceptance letter from the ISED is maintained in our files. CAB Identifier No: HK0015, Site Registration Number: 26103.

#### 4.5 Deviation from Standards

None

#### 4.6 Abnormalities from Standard Conditions

None



## 5 Radio Spectrum Technical Requirement

#### 5.1 RF Exposure

#### 5.1.1 Test Requirement:

CFR 47 Part 1.1310 Limit:

According to FCC Part1.1310: The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in Part1.1307(b)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm <sup>2</sup> )	Averaging time (minutes)				
	(A) Limits for Occupational/Controlled Exposure							
0.3-3.0	614	1.63	*100	6				
3.0-30	1842/f	4.89/f	*900/f <sup>2</sup>	6				
30-300	61.4	0.163	1.0	6				
300-1,500			f/300	6				
1,500-100,000			5	6				
	(B) Limits for Genera	al Population/Uncontrolled	d Exposure					
0.3-1.34	614	1.63	*100	30				
1.34-30	824/f	2.19/f	*180/f <sup>2</sup>	30				
30-300	27.5	0.073	0.2	30				
300-1,500			f/1500	30				
1,500-100,000			1.0	30				

#### TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

f = frequency in MHz

\* = Plane-wave equivalent power density

According to IEEE C95.3:2002 section 5.5.1.1, The power density S at a point on the axis at a distance d from a transmitting antenna is given by the Friis free-space transmission formula

$$S = \frac{PG}{4\pi d^2}$$

S = power density (mW/cm<sup>2</sup>)

*P* = the net power delivered to the antenna (*mW*)

G = gain of the antenna in linear scale

*d* = *distance between observation point and center of the radiator (cm)* 



#### 5.1.1 IC Radiofrequncy radiation

According to RSS-102 Issue 5, section 2.5.2 Exemption.

RF exposure evaluation is required if the separation distance between the user and the device's radiating element is greater than 20 cm, except when the device operates as follows:

below 20 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1 W (adjusted for tune-up tolerance);

at or above 20 MHz and below 48 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 22.48/f0.5W (adjusted for tune-up tolerance), where *f* is in MHz;

at or above 48 MHz and below 300 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 0.6 W (adjusted for tune-up tolerance);

at or above 300 MHz and below 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1.31 x 10-2 f 0.6834 W (adjusted for tune-up tolerance), where f is in MHz;

at or above 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 5 W (adjusted for tune-up tolerance).



#### 5.1.2 EUT RF Exposure Evaluation

Antenna Gain:

The maximum Gain measured in fully anechoic chamber is 1.0 in linear scale.

Output Power Into Antenna & RF Exposure Evaluation Distance:

For FCC;

FHSS:

Channel	Frequency (MHz)	Conduct power (including Tune-up tolerance) (dBm)	Conduct power (mW)	Power Density at R = 20 cm (mW/cm2)	Limit	MPE Ratios	Result
Low	2402	13.6	22.909	0.00456	1	0.00456	PASS
Middle	2440	14.6	28.840	0.00574	1	0.00574	PASS
High	2477	13.8	23.988	0.00477	1	0.00477	PASS

For IC:

FHSS:

Channel	Frequency (MHz)	Conduct power (including Tune-up tolerance) (dBm)	E.I.R.P (dBm)	E.I.R.P (W)	Limit (W)	Result
Low	2402	13.6	13.6	0.0229	2.7	PASS
Middle	2440	14.6	14.6	0.0288	2.7	PASS
High	2477	13.8	13.8	0.0240	2.7	PASS

Note: 1. Refer to report No. HKEM210800085402 for EUT test conducted power value. requirement.



Report No.: HKEM210800085403 Page: 11 of 11

## 6 Photographs

Remark: Photos refer to Appendix of HKEM2108000854AT.

- End of the Report -